

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of		)
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	Hund et al.	)
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Serial No.:	10/598,045	)
		)
Confirmation No.:	9493	)
		)
Filed:	August 16, 2006	)
		)
For:	SCANNING PROBE MICROSCOPE	)
		)
Customer No.:	022913	)

INFORMATION DISCLOSURE STATEMENT  
UNDER 37 C.F.R. § 1.97

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Please find, pursuant to 37 C.F.R. § 1.98(a)(1), the enclosed Form PTO-1449 which contains a list of all patents, publications, or other items that have come to the attention of one or more of the individuals designated in 37 C.F.R. § 1.56(c). While no representation is made that any of these references may be "prior art" within the meaning of that term under 35 U.S.C. §§ 102 or 103, the enclosed list of references is disclosed so as to fully comply with the duty of disclosure set forth in 37 C.F.R. § 1.56.

Moreover, while no representation is made that a specific search of office files or patent office records has been conducted or that no better art exists, the undersigned attorney of record believes that the enclosed art is the closest to the claimed invention (taken in its entirety) of which

the undersigned is presently aware, and no art which is closer to the claimed invention (taken in its entirety) has been knowingly withheld.

In accordance with 37 C.F.R. §§ 1.97 and 1.98, a copy of each of the foreign and nonpatent references or relevant portion thereof is also enclosed.

In accordance with 37 C.F.R. § 1.98(c), all English translations within the possession, custody, control or availability of anyone designated in 37 C.F.R. § 1.56(c) of each non-English reference, if any, are also enclosed.

Statement of Relevance of References Listed  
Unaccompanied by English Translation

In accordance with 37 C.F.R. § 1.98(a)(3), the following concise explanation of the relevance of each listed reference that is not in the English language and unaccompanied by a translation into English is provided.

NANOTOMOGRAPHY:

The invention relates to a device for determining the spatial distribution of properties of a notably heterogeneous sample (1). Said device comprises: a microscope (2) having a control (21) for the three-dimensional detection of the topography  $z_n(x, y)$  of the surface  $n$  of a sample (1); a probe (3) having a control (31) for the high resolution detection of one or more properties  $P_j$  of the sample (1) on the topography  $z_n(x, y)$  of the surface  $n$ ; a device (4) for removing material, for example a plasma etching device for etching with reactive gases or liquids or for chemomechanical polishing, which has a control (41) and by means of which in a removal process  $A_n, n+1$  a layer can be removed from the surface  $n$  of the sample (1); a computer-assisted image processing device (6) which is equipped such that from a sequence of surface topographies  $z_n(x, y)$  to  $z_{n+m}(x, y)$  determined by the microscope and from the properties  $P_j(z_n(x, y))$  to  $P_j(z_{n+m}(x, y))$  detected on said topographies it is able to generate a three-dimensional image of the sample.

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Respectfully submitted,

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